



To the participants of the Workshop on the Coupling of Synchrotron Radiation IR and X-rays with **Tip** based Scanning Probe Microscopies

ESRF, Grenoble, France
16-18 November 2005

Dear colleagues,

I take the opportunity of this recollection to thank you for participating to this first workshop on the coupling of Local Probe Microscopies and Synchrotron Radiation beams.

We are at the very early stages of this endeavour but we share the same enthusiasm for this effort that will give to synchrotron radiation new hands and new eyes to explore the well populated world below the micron.

New “eyes” because Local Probe Microscopies can “see” morphologies that are too small for the reach of optical microscopes and can then help in align them under the beams, but “eyes” also because there are situations where the tip *is* the detector or plays an instrumental role in detecting below the micron resolution. This is the case of the Infrared – SNOM.

And Local Probes give also the unique opportunity to put “hands on” the nanoworld because they can move, manipulate, separate, aggregate and position features that would be difficult to handle in other ways.

It will not be an easy task, and the lack of beamtime for testing and experimenting will make things even more difficult. It is my feeling though that the development that we are foreseeing is not just important, but necessary to get the right grasp on the nanoworld.

Good luck everybody.

Fabio Comin

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